

L Number	Hits	Search Text	DB	Time stamp
3	232	((gate with source with drain) with ("interlayer dielectric" ILD)) same contact	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:05
4	184	((gate with source with drain) with ("interlayer dielectric" ILD)) same contact) and (defin\$3 measur\$3 predict\$3 compar\$3 determin\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:12
5	45650	(drain with current) and (defin\$3 measur\$3 predict\$3 compar\$3 determin\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 12:54
6	14096	(drain with current) same (defin\$3 measur\$3 predict\$3 compar\$3 determin\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 12:57
7	3145	((drain with current) same (defin\$3 measur\$3 predict\$3 compar\$3 determin\$3)) and basic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 12:56
10	758051	(basic based base prim?ry) with (structure element)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:03
11	152647	((basic based base prim?ry) with (structure element)) same (defin\$3 measur\$3 predict\$3 compar\$3 determin\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:04
12	1340	((drain with current) same (defin\$3 measur\$3 predict\$3 compar\$3 determin\$3)) and basic) and ((basic based base prim?ry) with (structure element))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:03
14	4706	("interlayer dielectric" ILD) same contact	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:05
15	29	((drain with current) same (defin\$3 measur\$3 predict\$3 compar\$3 determin\$3)) and basic) and ((basic based base prim?ry) with (structure element))) and ("interlayer dielectric" ILD) same contact)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:05
16	2	predict\$3 with drain with current with (finished fabricated)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:17
17	2408	measur\$3 with drain with current	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:17
18	8717	compar\$3 with (finished fabricated)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:44

19	10	(measur\$3 with drain with current) same (compar\$3 with (finished fabricated))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:45
20	15753	determin\$3 with (finished fabricated)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:45
21	3	(measur\$3 with drain with current) same (determin\$3 with (finished fabricated))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 14:45
-	234	438/129.ccls.	USPAT; US-PGPUB	2003/12/23 10:05
-	122	438/130.ccls.	USPAT; US-PGPUB	2003/12/23 10:05
-	681	716/2.ccls.	USPAT; US-PGPUB	2003/12/23 10:05
-	507	716/10.ccls.	USPAT; US-PGPUB	2003/12/23 10:05
-	538	716/12.ccls.	USPAT; US-PGPUB	2003/12/23 10:40
-	5566	test\$3 with (redundant redundancy)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 10:05
-	2372	(test\$3 with (redundant redundancy)) and series	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 10:05
-	30951	test\$3 with (connecting wiring)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 10:05
-	1496	(test\$3 with (connecting wiring)) with number	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 10:05
-	5611	test\$3 with (redundant redundancy)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 10:45
-	169	(test\$3 with (redundant redundancy)) same series	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 10:11
-	414	716/for.491.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 10:40
-	220	438/10.ccls.	USPAT; US-PGPUB	2003/12/23 10:41
-	128238	gate with source with drain	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/23 10:45

-	10711	"interlayer dielectric" ILD	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/12/23 10:46
-	388	(gate with source with drain) with ("interlayer dielectric" ILD)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/12/23 10:46